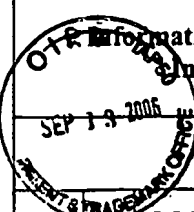


PTO-1449		Application No. 09/870,144		Applicant(s) Eva M. Sevick-Muraca, et al.		
		Docket Number 017575.0680 (TAMUS 1685)		Group Art Unit 3768	Filing Date May 30, 2001	
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EXAMINER Kasabhi Ray					DATE CONSIDERED 1-23-07	
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						
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